

**Notice of References Cited**

Application/Control No.

09/578,095

Applicant(s)/Patent Under  
Reexamination  
ARAGONES ET AL.

Examiner

Kandasamy Thangavelu

Art Unit

2123

Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,195,624	02-2001	Woodman et al.	703/7
	B	US-5,701,471	12-1997	Subramanyam	707/200
	C	US-6,405,160	06-2002	Djaja et al.	703/25
	D	US-2001/0020229	09-2001	Lash	705/3
	E	US-5,740,233	04-1998	cave et al.	379/112.06
	F	US-6,132,969	10-2000	Stoughton et al.	435/6
	G	US-5,748,508	05-1998	Baleanu	703/13
	H	US-5,686,359	11-1997	Meester et al.	438/664
	I	US-2002/0035570	05-2002	Kozam et al.	707/104.1
	J	US-6,230,095	05-2001	Wang	701/10
	K	US-5,822,218	10-1998	Moosa et al.	716/4
	L	US-6,370,454	04-2002	Moore	701/29
	M	US-6,490,506	12-2002	March	700/286

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Endrenyi et al., "Probalistic evaluation of the effect of maintenance on reliability - an Application", IEEE 1997
	V	Butler, "An expert system based framework for an incipient failure detection and predictive maintenance system", IEEE 1996
	W	Okogbaa et al., "Time series intervention analysis for Preventive/ Predictive maintenance management of multiunit systems", IEEE 1998.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**Application/Control No.  
09/578,095Applicant(s)/Patent Under  
Reexamination  
ARAGONES ET AL.Examiner  
Kandasamy ThangaveluArt Unit  
2123

Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,377,876	04-2002	Hedeen et al.	701/19
	B	US-6,408,258	06-2002	Richer	702/182
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.